Applicant(s)/Patent Under Application/Control No. Reexamination 10/782,289 VAN DE VELDE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2851 Christopher E. Mahoney U.S. PATENT DOCUMENTS Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY 353/101 04-2002 Lu, Chang-Hsing US-2002/0044264 Α 396/55 US-5,659,806 08-1997 Miyamoto et al. В 08-2004 Watanabe, Takashi 353/101 С US-6,773,117 353/101 06-2004 Runco, Virgil Sam US-2004/0114115 D 12-2002 353/101 Tachibana, Toshitaka US-6,491,401 Ε F US-US-G US-H ı US-US-US-US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date Classification Name Country MM-YYYY Ν 0 Ρ Q R s Т

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